For eight years, ETW has been the largest European event completely devoted to testing of microelectronics. Over the past years, ETW has grown and improved, in terms of its technical program, publication quality, and number of attendees. Starting in 2004, ETW has been renamed

IEEE European Test Symposium (ETS)

The IEEE European Test Symposium (ETS) continues to be the largest event in Europe entirely devoted to presenting and discussing trends, emerging results, hot topics, and practical applications in the area of electronic-based circuit and system testing. ETS’04 is the 9th edition of this annual event and took place in the beautiful city of Ajaccio, in Corsica, France. The technical program consisted of two full-day tutorials, two plenary keynote addresses, interactive paper presentations in two parallel tracks, four embedded tutorials, poster sessions, and two evening panels. Besides the regular technical program, there were two fringe workshops namely the 'Thames workshop' and the 'SDD workshop'. In addition, we also had several fringe meetings around the symposium as well as a very nice and attractive social event.

The proceedings in front of you contain all the papers presented at the symposium that have been selected from the set of papers submitted in the ‘formal’ category. Indeed, authors sending their work to the symposium may submit in the ‘formal’ category or in the ‘informal’ category. Then, both categories are reviewed and selected by the program committee but different evaluation criteria are used for each category. Only papers selected from the formal category are included in these IEEE proceedings.

We would like to take this opportunity to thanks all the authors, reviewers, and members of the program and organization committees for their valuable contributions to the success of the Symposium.

Michel Renovell
General Chair

Paolo Prinetto
Program Chair

Peter Muhmenthaler
Program Vice-Chair

Christian Landrault
Publication Chair